

Product Summary

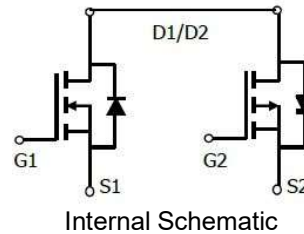
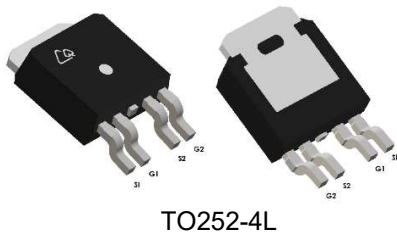
Description and Applications

| V(BR)DSS | | RDS(ON) max | ID |
|----------|------|-------------------------------------|-----|
| N-MOS | 40V | <30mΩ, VGS=10V <40mΩ, VGS=4.5V | 12A |
| P-MOS | -40V | <43mΩ, VGS=-10V <57mΩ, VGS=-4.5V | 12A |

The CQD609C uses trench power MOS technology to provide excellent RDS(ON) and low gate charge. The complementary MOSFETs may be used in H-bridge, inverters and other applications.

RoHS and Halogen-Free Compliant.

View and Internal Schematic Diagram



Marking Information



NOTE:
 LOGO - CQAOS
 609C- Part number coder
 F - Fab location code
 A - Assembly location code
 Y - Year code
 W - Week code
 L&T - Assembly lot code

Ordering Information

| Part Number | Case | Packaging |
|-------------|----------|-------------------|
| CQD609C | TO252-4L | 2,500/Tape & Reel |

Maximum Ratings (@TA = +25°C unless otherwise specified.)

| Parameters | Symbol | Max(N-MOS) | Max(P-MOS) | Units |
|---|---------|-------------|-------------|-------|
| Drain-Source Voltage | VDS | 40 | -40 | V |
| Gate-Source Voltage | VGS | 20 | -20 | V |
| Continuous Drain Current ^G | ID | TA=25°C | -12 | A |
| | | TA=100°C | -12 | |
| Pulsed Drain Current ^C | IDM | 40 | -30 | A |
| Power Dissipation ^B | PD | TA=25°C | 30 | W |
| | | TA=100°C | 9.3 | |
| Operating and Storage Temperature Range | TJ,TSTG | -55 to +175 | -55 to +175 | °C |

N-MOS Thermal Characteristics

| Characteristic | | Symbol | Typ | Max | Unit |
|--|--------------|-----------------|------|-----|---------------|
| Maximum Junction-to-Ambient ^A | $t \leq 10s$ | $R_{\theta JA}$ | 16.7 | 25 | $^{\circ}C/W$ |
| Maximum Junction-to-Ambient ^{A D} | Steady-State | | 40 | 50 | $^{\circ}C/W$ |
| Maximum Junction-to-Case | Steady-State | $R_{\theta JC}$ | 6.7 | 8 | $^{\circ}C/W$ |

N-MOS Electrical Characteristics (@ $T_A = +25^{\circ}C$ unless otherwise specified.)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-----|------|-----------|------------|
| STATIC PARAMETERS | | | | | | |
| BVDSS | Drain-Source Breakdown Voltage | $I_D=250\mu A, V_{GS}=0V$ | 40 | | | V |
| IDSS | Zero Gate Voltage Drain Current | $V_{DS}=40V, V_{GS}=0V$ | | | 1 | μA |
| | | $T_J=55^{\circ}C$ | | | 5 | |
| IGSS | Gate-Body leakage current | $V_{DS}=0V, V_{GS}=\pm 20V$ | | | ± 100 | nA |
| VGS(th) | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu A$ | 1 | 1.7 | 2.2 | V |
| RDS(ON) | Static Drain-Source On-Resistance | $V_{GS}=10V, I_D=12A$ | | 24.5 | 30 | m Ω |
| | | $T_J=125^{\circ}C$ | | 40 | 46 | |
| | | $V_{GS}=4.5V, I_D=8A$ | | 30 | 40 | |
| gFS | Forward Trans conductance | $V_{DS}=5V, I_D=12A$ | | 25.5 | | S |
| VSD | Diode Forward Voltage | $I_S=1A, V_{GS}=0V$ | | 0.76 | 1 | V |
| IS | Maximum Body-Diode Continuous Current | | | | 12 | A |
| DYNAMIC PARAMETERS | | | | | | |
| Ciss | Input Capacitance | | | 535 | | pF |
| Coss | Output Capacitance | $V_{GS}=0V, V_{DS}=15V,$ $f=1MHz$ | | 46 | | pF |
| Crss | Reverse Transfer Capacitance | | | 36 | | pF |
| Rg | Gate resistance | $V_{GS}=0V, V_{DS}=0V,$ $f=1MHz$ | 0.4 | 1.4 | 3.5 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Qg(10V) | Total Gate Charge | $V_{GS}=10V, V_{DS}=20V,$ $I_D=12A$ | | 11.3 | | nC |
| Qgs | Gate Source Charge | | | 3 | | nC |
| Qgd | Gate Drain Charge | | | 1.7 | | nC |
| tD(on) | Turn-On Delay Time | | | 4.4 | | ns |
| tr | Turn-On Rise Time | $V_{GS}=10V, V_{DS}=20V,$ $R_L=1.6\Omega, R_{GEN}=3\Omega$ | | 35 | | ns |
| tD(off) | Turn-Off Delay Time | | | 9.6 | | ns |
| tf | Turn-Off Fall Time | | | 23.6 | | ns |
| trr | Body Diode Reverse Recovery Time | $I_F=12A, dI/dt=100A/\mu s$ | | 6 | | ns |
| Qrr | Body Diode Reverse Recovery Charge | $I_F=12A, dI/dt=100A/\mu s$ | | 2 | | nC |

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 1oz. Copper, in a still air environment with $T_A=25^{\circ}C$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}=175^{\circ}C$, using junction-to-case thermal resistance and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=175^{\circ}C$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^{\circ}C$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu s$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted on 1in² FR-4 board with 1oz. Copper, in a still air environment with $T_A=25^{\circ}C$

G. The maximum current rating is package limited

P-MOS Thermal Characteristics

| Characteristic | | Symbol | Typ | Max | Unit |
|--|--------------|-----------------|------|-----|------|
| Maximum Junction-to-Ambient ^A | $t \leq 10s$ | $R_{\theta JA}$ | 16.8 | 25 | °C/W |
| Maximum Junction-to-Ambient ^{A D} | Steady-State | | 43 | 53 | °C/W |
| Maximum Junction-to-Case | Steady-State | $R_{\theta JC}$ | 3.3 | 5 | °C/W |

P-MOS Electrical Characteristics (@ $T_A = +25^\circ C$ unless otherwise specified.)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-----|-------|-----------|------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D = -250\mu A, V_{GS} = 0V$ | -40 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = -40V, V_{GS} = 0V$ | | | -1 | μA |
| | | $T_J = 55^\circ C$ | | | -5 | |
| I_{GSS} | Gate-Body leakage current | $V_{DS} = 0V, V_{GS} = \pm 20V$ | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = -250\mu A$ | -1 | -1.5 | -2.1 | V |
| $R_{DS(on)}$ | Static Drain-Source On-Resistance | $V_{GS} = -10V, I_D = -12A$ | | 34 | 43 | m Ω |
| | | $T_J = 125^\circ C$ | | 51 | 64 | |
| | | $V_{GS} = -4.5V, I_D = -8A$ | | 42 | 57 | |
| g_{FS} | Forward Trans conductance | $V_{DS} = -5V, I_D = -12A$ | | 23 | | S |
| V_{SD} | Diode Forward Voltage | $I_S = -1A, V_{GS} = 0V$ | | -0.76 | -1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | -12 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | | | 1048 | | pF |
| C_{oss} | Output Capacitance | $V_{GS} = 0V, V_{DS} = -20V,$ $f = 1MHz$ | | 93 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 85 | | pF |
| R_g | Gate resistance | $V_{GS} = 0V, V_{DS} = 0V,$ | 3.5 | 10 | 16.5 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| $Q_g(10V)$ | Total Gate Charge | $V_{GS} = -10V, V_{DS} = -20V,$ $I_D = -12A$ | | 24 | | nC |
| Q_{gs} | Gate Source Charge | | | 5.4 | | nC |
| Q_{gd} | Gate Drain Charge | | | 4.1 | | nC |
| $t_{D(on)}$ | Turn-On Delay Time | | | 8.7 | | ns |
| t_r | Turn-On Rise Time | $V_{GS} = -10V, V_{DS} = -20V,$ $R_L = 1.4\Omega, R_{GEN} = 3\Omega$ | | 62 | | ns |
| $t_{D(off)}$ | Turn-Off Delay Time | | | 60 | | ns |
| t_f | Turn-Off Fall Time | | | 78 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F = -12A, dI/dt = 100A/\mu s$ | | 27 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F = -12A, dI/dt = 100A/\mu s$ | | 6.5 | | nC |

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 1oz Copper, in a still air environment with $T_A = 25^\circ C$. The value in any given in any application depends on the user's specific board design

B. The power dissipation P_D is based on $T_{J(MAX)} = 175^\circ C$, using junction-to-case thermal resistance and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)} = 175^\circ C$. Ratings are based on low frequency and duty cycles to keep initial $T_J = 25^\circ C$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $< 300\mu s$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted on 1in² FR-4 board with 1oz. Copper, in a still air environment with $T_A = 25^\circ C$

G. The maximum current rating is package limited

N-MOS TYPICAL ELECTRICAL AND THERMAL CHARACTERIS

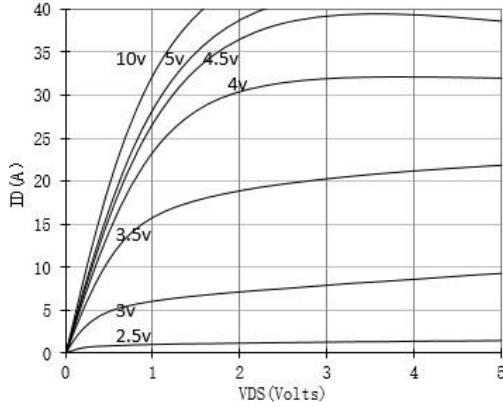


Figure 1: On-Region Characteristics (Note E)

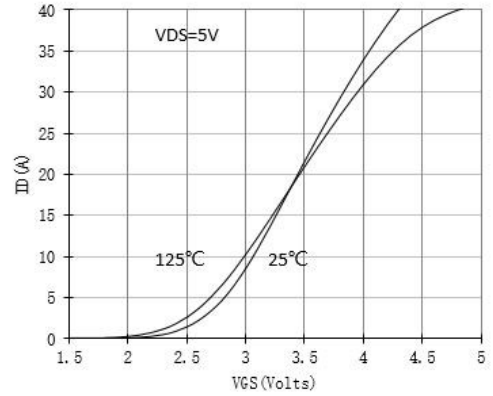


Figure 2 Transfer Characteristics (Note E)

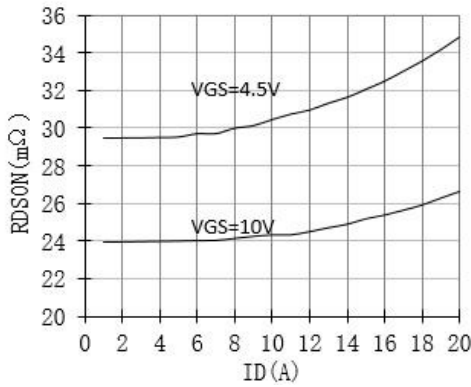


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

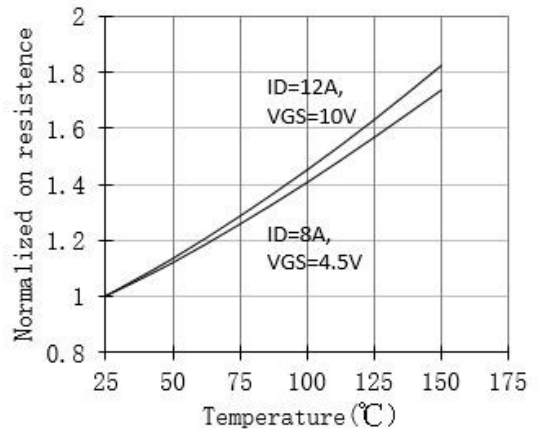


Figure 4: On-Resistance vs. Junction Temperature (Note E)

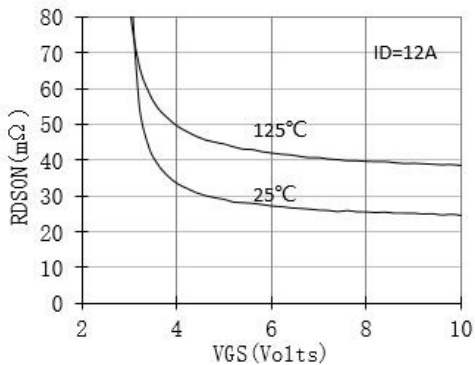


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

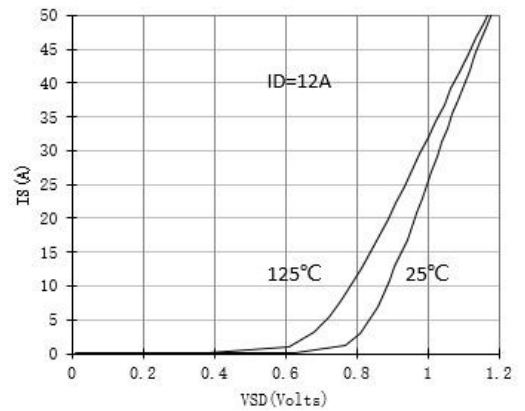


Figure 6: Body-Diode Characteristics (Note E)

N-MOS TYPICAL ELECTRICAL AND THERMAL CHARACTERIS

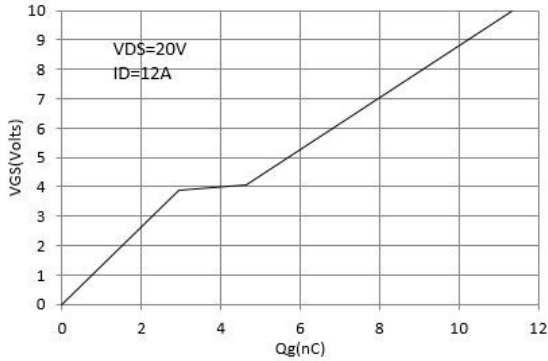


Figure 7: Gate-Charge Characteristics

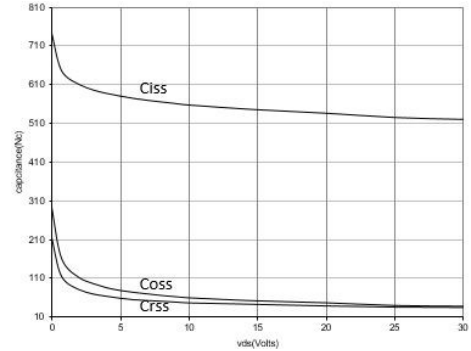


Figure 8: Capacitance Characteristics

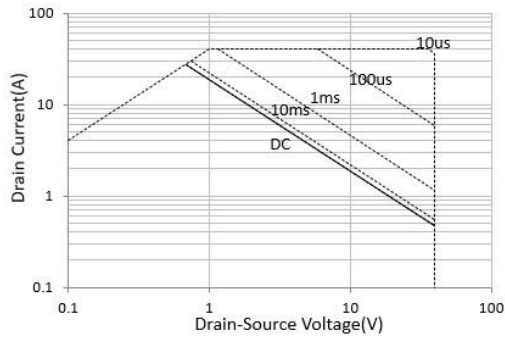


Figure 9: Maximum Forward Biased Safe Operating Area

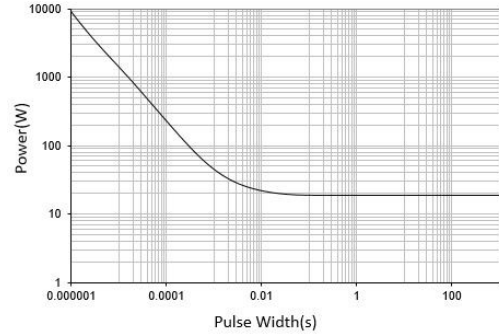


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

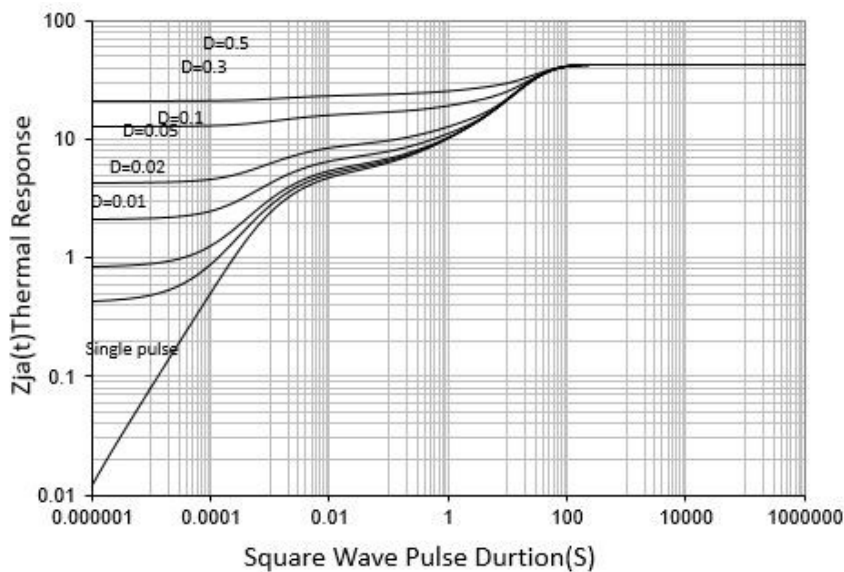


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

P-MOS TYPICAL ELECTRICAL AND THERMAL CHARACTERIS

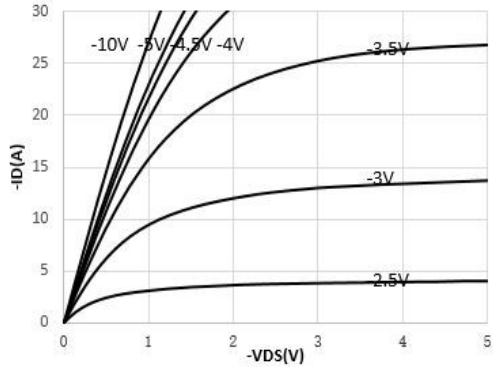


Figure 1: On-Region Characteristics (Note E)

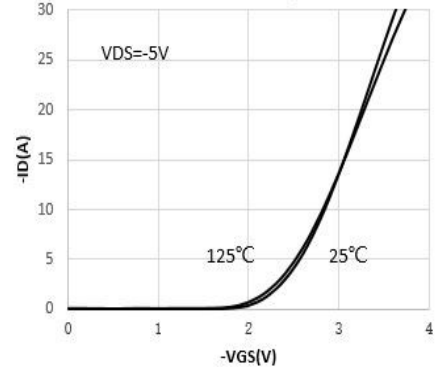


Figure 2: Transfer Characteristics (Note E)

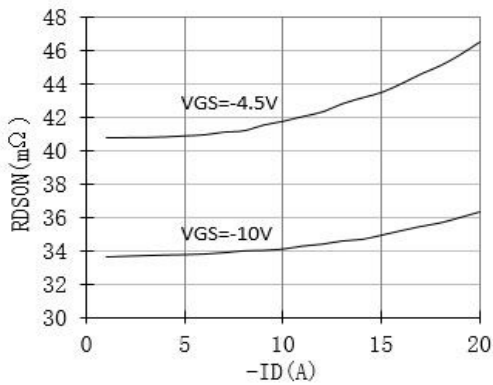


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

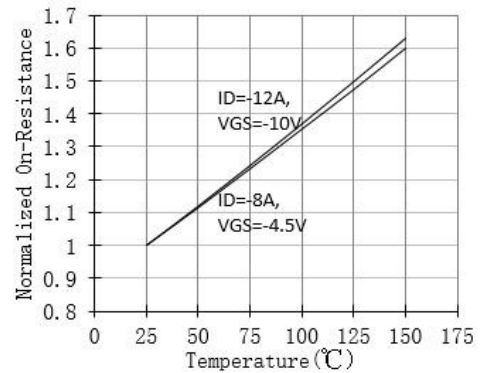


Figure 4: On-Resistance vs. Junction Temperature (Note E)

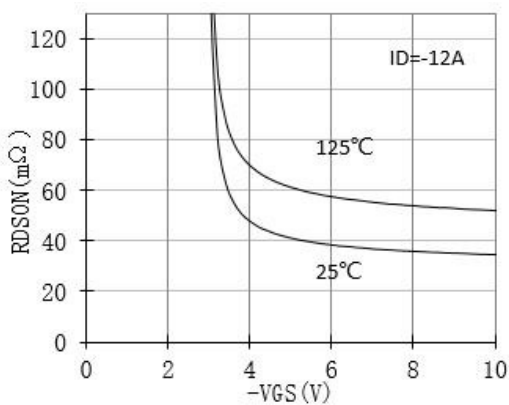


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

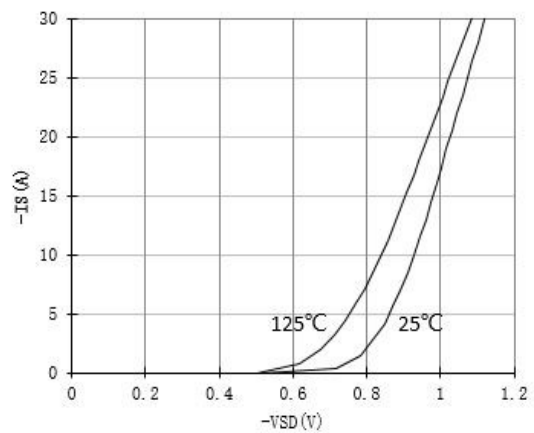


Figure 6: Body-Diode Characteristics (Note E)

P-MOS TYPICAL ELECTRICAL AND THERMAL CHARACTERIS

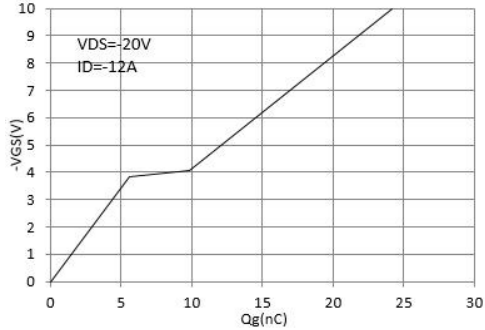


Figure 7: Gate-Charge Characteristics

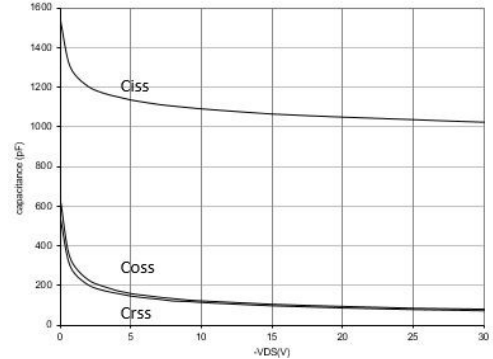


Figure 8: Capacitance Characteristics

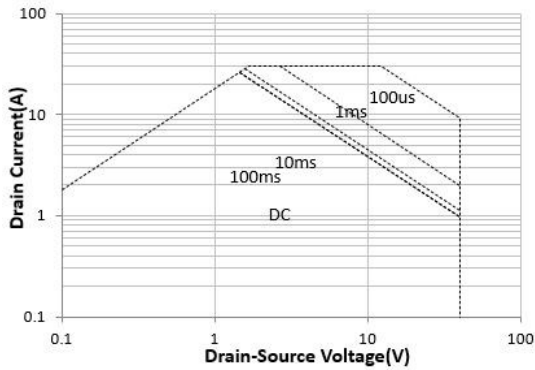


Figure 9: Maximum Forward Biased Safe Operating Area

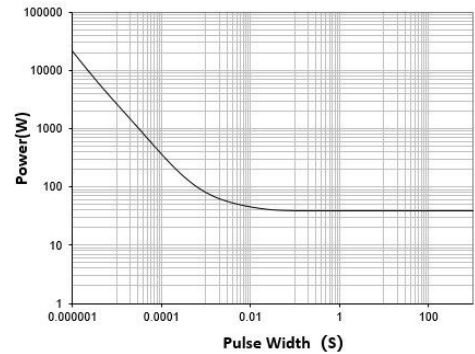


Figure 10: Single Pulse Power Rating Junction-to-Case

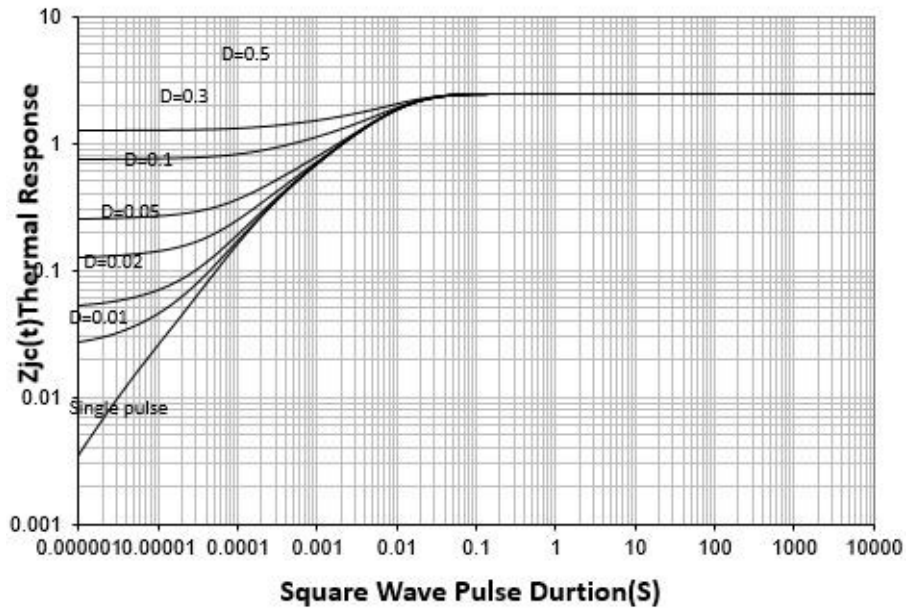


Figure 11: Normalized Maximum Transient Thermal Impedance

单击下面可查看定价，库存，交付和生命周期等信息

[>>CQAOS](#)